ACPL-K43T, ACPL-K44T

Automotive R²Coupler[®] Wide Operating Temperature 1 MBd Digital Optocoupler in a Stretched 8-Pin Surface Mount Plastic Package



Data Sheet



Description

The ACPL-K43T is a single channel, high temperature, high CMR, high speed digital optocoupler in an eight lead miniature footprint specifically used in the automotive applications. The ACPL-K44T is a dual channel equivalent of the ACPL-K43T. Both products are available in the stretched SO-8 package outline, designed to be compatible with standard surface mount processes.

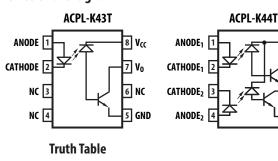
This digital optocoupler uses an insulating layer between the light emitting diode and an integrated photo detector to provide electrical insulation between input and output. Separate connections for the photodiode bias and output transistor collector increase the speed up to a hundred times over that of a conventional photo-transistor coupler by reducing the base-collector capacitance.

Avago R²Coupler® isolation products provide with reinforced insulation and reliability that delivers safe signal isolation critical in automotive and high temperature industrial applications.

Functional Diagram

LED

ON



Vo

LOW HIGH

Note: The connection of a 0.1 μF bypass capacitor between pins 5 and 8 is recommended.

Features

- High Temperature and Reliability low speed digital interface for Automotive Application
- \bullet Ultra low drive for status feedback at I_F = 0.8 mA or 1.5 mA
- 30 kV/ μ s (Typ) High Common-Mode Rejection at $V_{CM} = 1500 \text{ V}$
- Compact, Auto-Insertable Stretched SO8 Packages
- Qualified to AEC Q100 Grade 1 Test Guidelines
- Wide Operating Temperature Range: -40°C to +125°C
- High Speed: 1 MBd
- Low Propagation Delay: 1 μs max. at I_F = 10 mA
- Worldwide Safety Approval:
 - UL 1577 approval, 5 kV_{RMS}/1 min.
 - CSA Approval
 - IEC/EN/DIN EN 60747-5-5

Applications

- Automotive IPM Driver for DC-DC converters and motor inverters
- Status Feedback and Wake-Up Signal Isolation
- CANBus and SPI Communications Interface
- High Temperature Digital/Analog Signal Isolation

CAUTION: It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD.

Ordering Information

Specify part number followed by option number (if desired).

Part number	Option (RoHS Compliant)	Package	Surface Mount	Tape & Reel	UL 5000 V _{rms} / 1 Minute rating	IEC/EN/DIN EN 60747-5-5	Quantity
ACPL-K43T	-000E	Stretched	Χ		Χ		80 per tube
	-060E	SO-8	Х		Х	Х	80 per tube
	-500E		Χ	Х	Χ		1000 per reel
	-560E		Х	Х	Х	Х	1000 per reel
ACPL-K44T	-000E	Stretched	Χ		Χ		80 per tube
	-060E	SO-8	Χ		Χ	Χ	80 per tube
	-500E		Χ	Χ	Χ		1000 per reel
	-560E		Χ	Х	X	Х	1000 per reel

To order, choose a part number from the part number column and combine with the desired option from the option column to form an order entry.

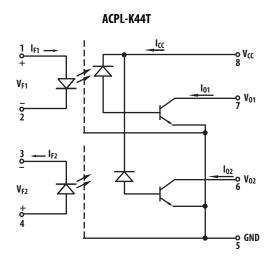
Example 1:

ACPL-K43T-560E to order product of SSO-8 Surface Mount package in Tape and Reel packaging with IEC/EN/DIN EN 60747-5-5 Safety Approval in RoHS compliant.

Option datasheets are available. Contact your Avago sales representative or authorized distributor for information.

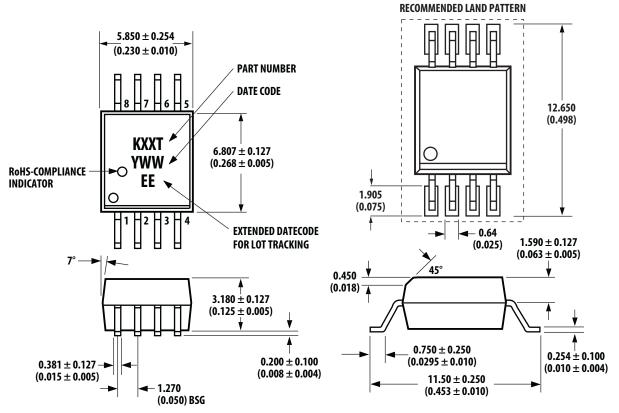
Schematic

ACPL-K43T ANODE O 1 V_F CATHODE O 3 SHIELD 5 GND



USE OF 0.1 μF bypass capacitor connected between Pins 5 and 8 is recommended.

Package Outline Dimensions (Stretched SO8)



Dimensions in millimeters and (inches).

Note:

Lead coplanarity = 0.1 mm (0.004 inches). Floating lead protrusion = 0.25mm (10mils) max.

Recommended Pb-Free IR Profile

Recommended reflow condition as per JEDEC Standard, J-STD-020 (latest revision). Note: Non-halide flux should be used.

Regulatory Information

The ACPL-K43T and ACPL-K44T are approved by the following organizations:

ш

UL 1577, component recognition program up to $V_{ISO} = 5 \text{ kV}_{RMS}$.

CSA

CSA Component Acceptance Notice #5.

IEC/EN/DIN EN 60747-5-5

IEC 60747-5-5 EN 60747-5-5 DIN EN 60747-5-5

Insulation and Safety Related Specifications

Parameter	Symbol	ACPL-K43T ACPL-K44T	Units	Conditions
Minimum External Air Gap (Clearance)	L(101)	8	mm	Measured from input terminals to output terminals, shortest distance through air.
Minimum External Tracking (Creepage)	L(102)	8	mm	Measured from input terminals to output terminals, shortest distance path along body.
Minimum Internal Plastic Gap (Internal Clearance)		0.08	mm	Through insulation distance conductor to conductor, usually the straight line distance thickness between the emitter and detector.
Tracking Resistance (Comparative Tracking Index)	CTI	175	V	DIN IEC 112/VDE 0303 Part 1
Isolation Group (DIN VDE0109)		Illa		Material Group (DIN VDE 0109)

IEC/EN/DIN EN 60747-5-5 Insulation Related Characteristic (Option 060E and 560E)

Description	Symbol	Characteristic	Units
Installation classification per DIN VDE 0110/1.89, Table 1			
for rated mains voltage $\leq 150 V_{rms}$		I – IV	
for rated mains voltage \leq 300 V_{rms}		I – IV	
for rated mains voltage \leq 450 V_{rms}		I – IV	
for rated mains voltage \leq 600 V_{rms}		I – IV	
for rated mains voltage $\leq 1000 V_{rms}$		I – III	
Climatic Classification		55/100/21	
Pollution Degree (DIN VDE 0110/1.89)		2	
Maximum Working Insulation Voltage	V_{IORM}	1140	V_{peak}
Input to Output Test Voltage, Method b*	V_{PR}	2137	V _{peak}
$V_{IORM} \times 1.875 = V_{PR}$, 100% Production Test with $t_m = 1$ sec, Partial discharge < 5 pC			•
Input to Output Test Voltage, Method a*	V _{PR}	1824	V _{peak}
V_{IORM} x 1.6 = V_{PR} , Type and Sample Test, t_m = 10 sec, Partial discharge < 5 pC			
Highest Allowable Overvoltage (Transient Overvoltage t _{ini} = 60 sec)	V _{IOTM}	8000	V _{peak}
Safety Limiting Values (Maximum values allowed in the event of a failure)			
Case Temperature	T_S	175	°C
Input Current	Is, INPUT	230	mA
Output Power	Ps, output	600	mW
Insulation Resistance at T_S , $V_{IO} = 500 \text{ V}$	R _S	>10 ⁹	Ω

Absolute Maximum Ratings

Parameter		Symbol	Min.	Max.	Units	Note
Storage Temperature		T _{STG}	-55	150	°C	
Operating Ambient Tempe	rature	T _A	-40	125	°C	
Average Forward Input Cui	rrent	I _{F(avg)}		20	mA	
Peak Forward Input Curren (50% duty cycle, 1 ms pulse	I _{F(peak)}		40	mA		
Peak Transient Input Curre (≤ 1 μs pulse width, 300 ps	I _{F(trans)}		100	mA		
Reversed Input Voltage		V _R		5	V	
Input Power Dissipation (p	er channel)	P _{IN}		30	mW	
Output Power Dissipation		Po		100	mW	
Average Output Current		I _O		8	mA	
Peak Output Current		I _{O(pk)}		16	mA	
Supply Voltag		V _{CC}	-0.5	30	V	
Output Voltage		Vo	-0.5	20	V	
Lead Soldering Cycle	Temperature			260	°C	
	Time			10	S	

Recommended Operating Conditions

Parameter	Symbol	Min.	Max.	Units	Note
Supply Voltage	V_{CC}		20	V	
Operating Temperature	T _A	-40	125	°C	

Electrical Specifications (DC)

Over recommended operating $T_A = -40^{\circ}$ C to 125° C, unless otherwise specified

Parameter	Sym.	Min.	Тур.	Max.	Units	Test Conditions	Fig.	Note
Current Transfer Ratio	CTR	32	65	100	%	$T_A = 25$ °C $V_{CC} = 4.5 \text{ V}, V_O = 0.4 \text{ V}, I_F = 10 \text{ mA}$	1, 2, 4	1
		24	65		_			
		33	160		_	$V_{CC} = 4.5 \text{ V}, V_O = 0.4 \text{ V}, I_F = 1.5 \text{ mA}$	_	
		25	165		_	$V_{CC} = 4.5 \text{ V}, V_{O} = 0.4 \text{ V}, I_{F} = 0.8 \text{ mA}$		
Logic Low Output	V_{OL}		0.1	0.5	V	$V_{CC} = 4.5 \text{ V}, I_O = 2.4 \text{ mA}, I_F = 10 \text{ mA}$		
Voltage			0.1			$V_{CC} = 4.5 \text{ V}, I_O = 0.5 \text{ mA}, I_F = 1.5 \text{ mA}$		
			0.1			$V_{CC} = 4.5 \text{ V}, I_O = 0.2 \text{ mA}, I_F = 0.8 \text{ mA}$		
Logic High Output	I_{OH}		3x10 ⁻⁵	0.5	μΑ	$T_A = 25$ °C $V_O = V_{CC} = 5.5 \text{ V}$ $I_F = 0 \text{ mA}$	11, 12	
Current			8x10 ⁻⁵	5		$V_O = V_{CC} = 20 \text{ V}$		
Logic Low Supply	I_{CCL}		85	200	μΑ	$I_F = 10 \text{ mA}, V_O = \text{open}, V_{CC} = 20 \text{ V}$		
Current (per Channel)			15			$I_F = 1.5 \text{ mA}, V_O = \text{open}, V_{CC} = 20 \text{ V}$		
Logic High Supply	I _{CCH}		0.02	1	μΑ	$T_A = 25^{\circ}C$ $I_F = 0 \text{ mA}, V_O = \text{open}, V_{CC} = 20 \text{ V}$		
Current (per Channel)				2.5				
Input Forward Voltage	V_{F}	1.45	1.55	1.75	V	$T_A = 25^{\circ}C$ $I_F = 10 \text{ mA}$	3	_
		1.25	1.55	1.85				
Input Reversed Breakdown Voltage	BV_R	5			V	$I_R = 10 \mu A$		
Temperature Coefficient	ΔV_F /		-1.5		mV/°C	I _F =10 mA		
of Forward Voltage	ΔT_{A}		-1.8			I _F =1.5 mA		
Input Capacitance	C _{IN}		90		рF	$F = 1 \text{ MHz}, V_F = 0$		

Switching Specifications (AC)

Over recommended operating ($T_A = -40^{\circ}\text{C}$ to 125°C), $V_{CC} = 5.0 \text{ V}$ unless otherwise specified.

Parameter	Symbol	Min	Тур	Max	Units	Test Conditio	ons		Fig.	Note
Propagation Delay Time to Logic Low at Output	t _{PHL}	0.07	0.15	0.8 1.0	_ μs _	T _A = 25°C	$I_F = 10 \text{ mA},$ $R_L = 1.9 \text{ k}\Omega$	Pulse: $f = 10 \text{ kHz}$, Duty cycle = 50%, $V_{CC} = 5.0 \text{ V}$, $C_{I} = 15 \text{ pF}$,	5, 6, 7, 8, 9, 10, 13	2, 3
атомрат			0.7	5	_		$I_F = 1.5 \text{ mA},$ $R_L = 10 \text{ k}\Omega$	V _{THHL} = 1.5 V		
			1	10			$I_F = 0.8 \text{ mA},$ $R_L = 27 \text{ k}\Omega$			
Propagation Delay	t_{PLH}	0.15	0.5	0.8	μs	$T_A = 25$ °C	$I_F = 10 \text{ mA},$	Pulse: f = 10 kHz,	5, 6, 7,	2, 3
Time to Logic High at Output		0.03		1.0	_		$R_L = 1.9 \text{ k}\Omega$	Duty cycle = 50%, V _{CC} = 5.0 V, C _L = 15 pF,	8, 9, 10, 13	
αι σαιραί			0.9	5	_		$I_F = 1.5 \text{ mA},$ $R_L = 10 \text{ k}\Omega$	V _{THHL} = 2.0 V		
			2	10			$I_F = 0.8 \text{ mA},$ $R_L = 27 \text{ k}\Omega$			
Pulse Width	PWD		0.35	0.45	μs	$T_A = 25$ °C	Pulse: f = 10 kHz, Duty cycle = 50%, I_F = 10 mA, V_{CC} = 5.0 V, R_L = 1.9 kΩ,			2, 3, 4
Distortion				0.85						
Propagation Delay	PDD		0.35	0.5	μs	$T_A = 25$ °C		kHz, Duty cycle = 50%,		2, 3, 5
Difference Between Any 2 Parts				0.9			$^{-}$ I _F = 10 mA, V _{CC} = 5.0 V, R _L = 1.9 kΩ, C _L = 15 pF, V _{THHL} = 1.5 V,			
Common Mode Transient Immunity at Logic High Output	CM _H	15	30		kV/μs	$I_F = 0 \text{ mA}$	$V_{CM} = 1500 V_{p-p}, R_L = 1.9 k\Omega,$ $V_{CC} = 5 V, T_A = 25^{\circ}C$		14	6
Common Mode Transient Immunity at Logic Low Output	CM _L	15	30		kV/μs	$I_F = 10 \text{ mA}$				
Common Mode Transient Immunity at Logic High Output	CM _H		5		kV/μs	$I_F = 0 \text{ mA}$	$V_{CM} = 1500 \text{ V}$ $V_{CC} = 5 \text{ V}, T_A$	V _{p-p} , R _L = 10 kΩ, = 25°C	14	6
Common Mode Transient Immunity at Logic Low Output	CM _L		5		kV/μs	I _F = 1.5 mA	_			

Package Characteristics

Parameter	Symbol	Min.	Тур.	Max.	Units	Test Conditions	Fig.	Note
Input-Output Momentary Withstand Voltage*	V_{ISO}	5000			V_{RMS}	RH \leq 50%, t = 1 min., T _A = 25°C		7, 8
Input-Output Resistance	R _{I-O}		10 ¹⁴		Ω	V _{I-O} = 500 Vdc		7
Input-Output Capacitance	C _{I-O}		0.6		pF	$f = 1 MHz, V_{I-O} = 0 Vdc$		7

^{*} The Input-Output Momentary Withstand Voltage is a dielectric voltage rating that should not be interpreted as an input-output continuous voltage rating.

Notes:

- 1. Current Transfer Ratio in percent is defined as the ratio of output collector current, I_O, to the forward LED input current, I_F, times 100.
- 2. Use of a 0.1 μF bypass capacitor connected between pins 5 and 8 is recommended.
- 3. The 1.9 k Ω load represents 1 TTL unit load of 1.6 mA and the 5.6 k Ω pull-up resistor.
- 4. Pulse Width Distortion (PWD) is defined as $|t_{PHL} t_{PLH}|$ for any given device.
- 5. The difference between t_{PLH} and t_{PHL} between any two parts under the same test condition.
- 6. Common transient immunity in a Logic High level is the maximum tolerable (positive) dV_{CM}/dt on the rising edge of the common mode pulse, V_{CM} , to assure that the ouput will remain in a Logic High state (i.e., $V_O > 2.0 \text{ V}$). Common mode transient immunity in a Logic Low level is the maximum tolerable (negative) dV_{CM}/dt on the falling edge of the common mode pulse signal, V_{CM} to assure that the output will remain in a Logic Low state (i.e., $V_O < 0.8 \text{ V}$).
- 7. Device considered a two terminal device: pins 1, 2, 3 and 4 shorted together, and pins 5, 6, 7 and 8 shorted together.
- 8. In accordance with UL 1577, each optocoupler is proof tested by applying an insulation test voltage ≥ 6000 V_{RMS} for 1 second.

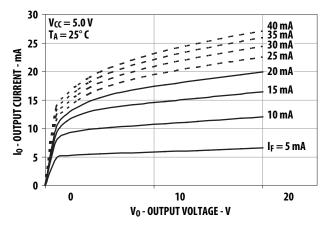
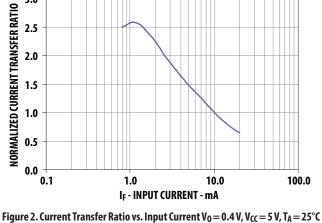


Figure 1. DC and Pulsed Transfer Characteristics



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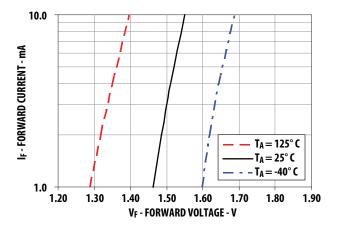


Figure 3. Input Current vs. Forward Voltage

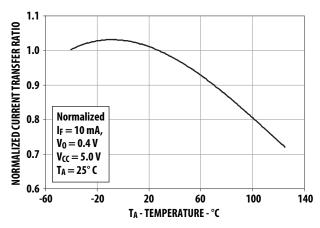


Figure 4. Current Transfer Ratio vs. Temperature

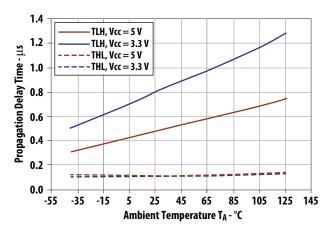


Figure 5, Propagation Delay Time vs. Temperature $I_F = 10 \text{ mA}$, $R_L = 1.9 \text{ k}\Omega$, $C_L = 15 \text{ pF}$

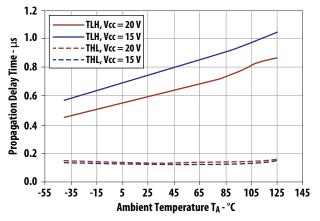


Figure 6. Propagation Delay Time vs. Temperature $I_F = 10 \text{ mA}$, $R_L = 20 \text{ k}\Omega$, $C_L = 100 \text{ pF}$

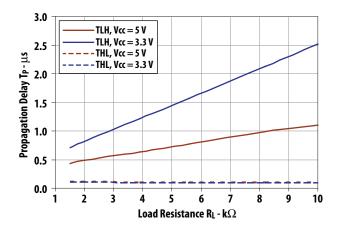


Figure 7. Propagation Delay Time vs. Load Resistance

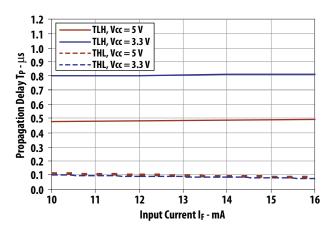


Figure 9. Propagation Delay Time vs. Input Current RL = 1.9 k Ω , CL = 15 pF, TA = 25°C

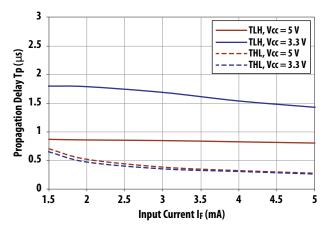


Figure 10a. Propagation Delay Time vs. Input Current R_L = 10 k Ω , C_L = 15 pF, T_A = 25°C

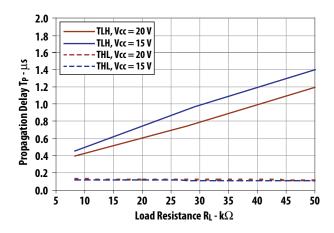


Figure 8. Propagation Delay Time vs. Load Resistance

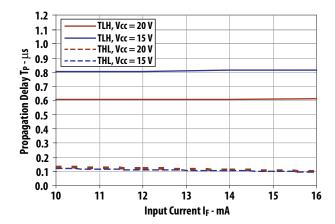


Figure 10. Propagation Delay Time vs. Input Current $R_L = 20 \text{ k}\Omega$, $C_L = 15 \text{ pF, } T_A = 25^{\circ}\text{C}$

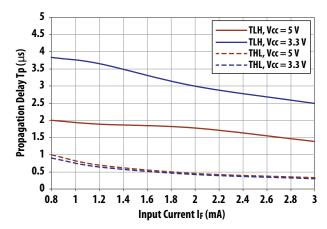
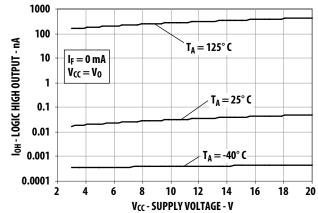


Figure 10b. Propagation Delay Time vs. Input Current $R_L=27~k\Omega$, $C_L=15~pF$, $T_A=25^{\circ}C$





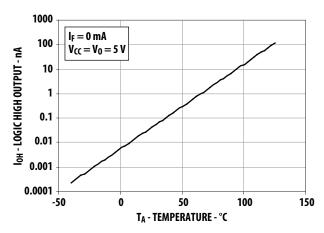
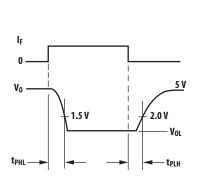


Figure 12. Logic High Output Current vs. Temperature



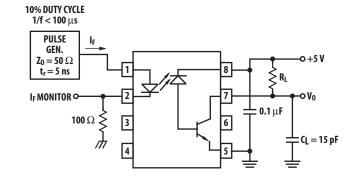
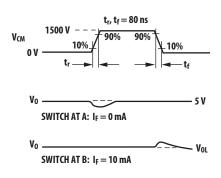


Figure 13. Switching Test Circuit



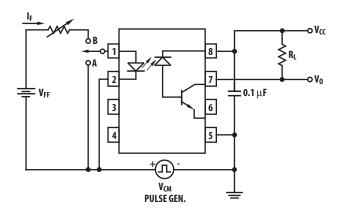


Figure 14. Test Circuit for Transient Immunity and Typical Waveforms

Thermal Resistance Model for ACPL-K43T

The diagram of ACPL-K43T for measurement is shown in Figure 15. Here, one die is heated first and the temperatures of all the dice are recorded after thermal equilibrium is reached. Then, the 2nd die is heated and all the dice temperatures are recorded. With the known ambient temperature, the die junction temperature and power dissipation, the thermal resistance can be calculated. The thermal resistance calculation can be cast in matrix form. This yields a 2 by 2 matrix for our case of two heat sources.

$$\left|\begin{array}{cc} R_{11} & R_{12} \\ R_{21} & R_{22} \end{array}\right| \quad X \quad \left|\begin{array}{c} P_1 \\ P_2 \end{array}\right| \quad = \quad \left|\begin{array}{c} \Delta T_1 \\ \Delta T_2 \end{array}\right|$$

R₁₁: Thermal Resistance of Die1 due to heating of Die1 (°C/W)

R₁₂: Thermal Resistance of Die1 due to heating of Die2 (°C/W)

R₂₁: Thermal Resistance of Die2 due to heating of Die1 (°C/W)

R₂₂: Thermal Resistance of Die2 due to heating of Die2 (°C/W)

P₁: Power dissipation of Die1 (W)

P₂: Power dissipation of Die2 (W)

T₁: Junction temperature of Die1 due to heat from all dice (°C)

T₂: Junction temperature of Die2 due to heat from all dice (°C)

T_a: Ambient temperature (°C)

 ΔT_1 : Temperature difference between Die1 junction and ambient (°C)

ΔT₂: Temperature deference between Die2 junction and ambient (°C)

$$T_1 = (R_{11} \times P_1 + R_{12} \times P_2) + T_a$$

$$T_2 = (R_{21} \times P_1 + R_{22} \times P_2) + T_a$$

Measurement data on a low K board:

$$R_{11} = 160^{\circ}\text{C/W}, R_{12} = R_{21} = 74^{\circ}\text{C/W}, R_{22} = 115^{\circ}\text{C/W}$$

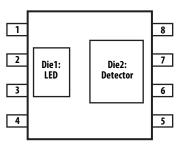


Figure 15. Diagram of ACPL-K43T for measurement

Thermal Resistance Model for ACPL-K44T

The diagram of ACPL-K44T for measurement is shown in Figure 16. Here, one die is heated first and the temperatures of all the dice are recorded after thermal equilibrium is reached. Then, the 2nd ,3rd and 4th die is heated and all the dice temperatures are recorded. With the known ambient temperature, the die junction temperature and power dissipation, the thermal resistance can be calculated. The thermal resistance calculation can be cast in matrix form. This yields a 4 by 4 matrix for our case of two heat sources.

R₁₁: Thermal Resistance of Die1 due to heating of Die1 (°C/W)

R₁₂: Thermal Resistance of Die1 due to heating of Die2 (°C/W)

R₁₃: Thermal Resistance of Die1 due to heating of Die3 (°C/W)

R₁₄: Thermal Resistance of Die1 due to heating of Die4 (°C/W)

R₂₁: Thermal Resistance of Die2 due to heating of Die1 (°C/W)

R₂₂: Thermal Resistance of Die2 due to heating of Die2 (°C/W)

R₂₃: Thermal Resistance of Die2 due to heating of Die3 (°C/W)

R₂₄: Thermal Resistance of Die2 due to heating of Die4 (°C/W)

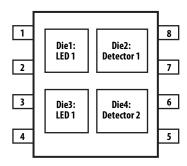


Figure 16. Diagram of ACPL-K44T for measurement

- R₃₁: Thermal Resistance of Die3 due to heating of Die1 (°C/W)
- R₃₂: Thermal Resistance of Die3 due to heating of Die2 (°C/W)
- R₃₃: Thermal Resistance of Die3 due to heating of Die3 (°C/W)
- R₃₄: Thermal Resistance of Die3 due to heating of Die4 (°C/W)
- R₄₁: Thermal Resistance of Die4 due to heating of Die1 (°C/W)
- $R_{42}\,$: Thermal Resistance of Die4 due to heating of Die2 (°C/W)
- R₄₃: Thermal Resistance of Die4 due to heating of Die3 (°C/W)
- R₄₄: Thermal Resistance of Die4 due to heating of Die4 (°C/W)
- P₁: Power dissipation of Die1 (W)
- P₂: Power dissipation of Die2
- P₃: Power dissipation of Die3 (W)
- P₄: Power dissipation of Die4
- T₁: Junction temperature of Die1 due to heat from all dice (°C)
- T₂: Junction temperature of Die2 due to heat from all dice (°C)
- T₃ : Junction temperature of Die3 due to heat from all dice (°C)
- T₄: Junction temperature of Die4 due to heat from all dice (°C)
- T_a: Ambient temperature (°C)
- ΔT_1 : Temperature difference between Die1 junction and ambient (°C)
- ΔT_2 : Temperature deference between Die2 junction and ambient (°C)
- ∆T₃: Temperature difference between Die3 junction and ambient (°C)
- ΔT₄: Temperature deference between Die4 junction and ambient (°C)
- $T_1 = (R11 \times P1 + R12 \times P2 + R13 \times P3 + R14 \times P4) + Ta (1)$
- $T_2 = (R21 \times P1 + R22 \times P2 + R23 \times P3 + R24 \times P4) + Ta -- (2)$
- $T_3 = (R31 \times P1 + R32 \times P2 + R33 \times P3 + R34 \times P4) + Ta -- (3)$
- $T_4 = (R41 \times P1 + R42 \times P2 + R43 \times P3 + R44 \times P4) + Ta -- (4)$

Measurement data on a low K board:

R ₁₁	R ₁₂	R ₁₃	R ₁₄	R ₂₁	R ₂₂	R ₂₃	R ₂₄	R ₃₁	R ₃₂	R ₃₃	R ₃₄	R ₄₁	R ₄₂	R ₄₃	R ₄₄
160	76	76	76	76	115	76	76	76	76	160	76	76	76	76	115

